Signetics

FAST 74F114
Flip-Flop

Dual J-K Negative Edge-Triggered Flip-Flop
With Common Clock And Reset
Product Specification

FAST Products

DESCRIPTION

The 74F114, Dual Negative Edge-Triggered JK-Type Flip-Flop with common clock and reset inputs, features individual J, K, Clock ($\overline{CP}$), Set ($\overline{S}_D$) and Reset ($\overline{R}_D$) inputs, true and complementary outputs.

The $\overline{S}_D$ and $\overline{R}_D$ inputs, when Low, set or reset the outputs as shown in the Function Table regardless of the level at the other inputs.

A High level on the clock ($\overline{CP}$) input enables the J and K inputs and data will be accepted. The logic levels at the J and K inputs may be allowed to change while the $\overline{CP}$ is High and flip-flop will perform according to the Function Table as long as minimum setup and hold times are observed. Output changes are initiated by the High-to-Low transition of the $\overline{CP}$.

TYPE	TYPICAL f_{MAX}	TYPICAL SUPPLY CURRENT (TOTAL)
N74F114	100MHz	15mA

ORDERING INFORMATION

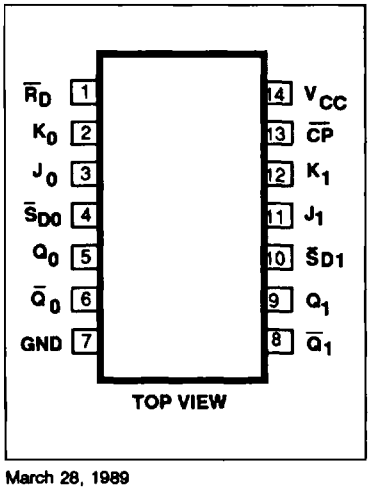
PACKAGES	COMMERCIAL RANGE V_{CC} = 5V±10%; T_A = 0°C to +70°C
14-Pin Plastic DIP	N74F114N
14-Pin Plastic SO	N74F114D

INPUT AND OUTPUT LOADING AND FAN-OUT TABLE

PINS	DESCRIPTION	74F(U.L.) HIGH/LOW	LOAD VALUE HIGH/LOW
J_0, J_1	J inputs	1.0/1.0	20µA/0.6mA
K_0, K_1	K inputs	1.0/1.0	20µA/0.6mA
$\overline{S}_{D0}$, $\overline{S}_{D1}$	Set inputs (active Low)	1.0/5.0	20µA/3.0mA
$\overline{R}_D$	Reset input (active Low)	1.0/10.0	20µA/6.0mA
$\overline{CP}$	Clock Pulse input (active falling edge)	1.0/8.0	20µA/4.8mA
Q_0,$\overline{Q}_0$; Q_1, $\overline{Q}_1$	Data outputs	50/33	1.0mA/20mA

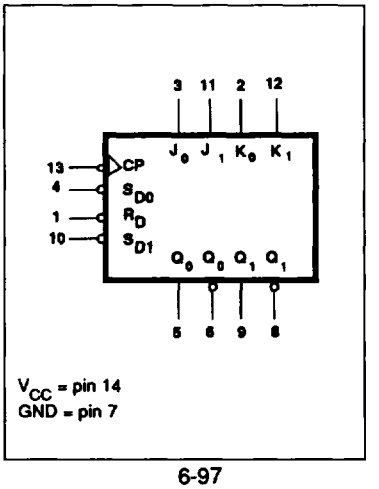
NOTE:
One (1.0) FAST Unit Load is defined as: 20µA in the High state and 0.6mA in the Low state.

PIN CONFIGURATION



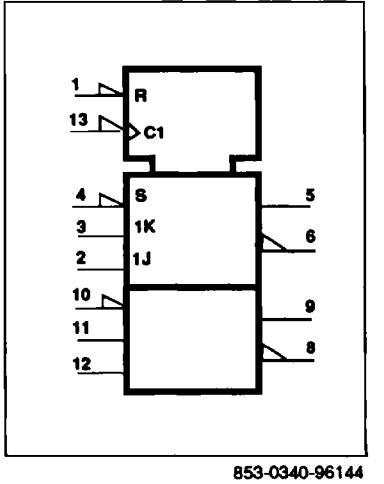
TOP VIEW

LOGIC SYMBOL

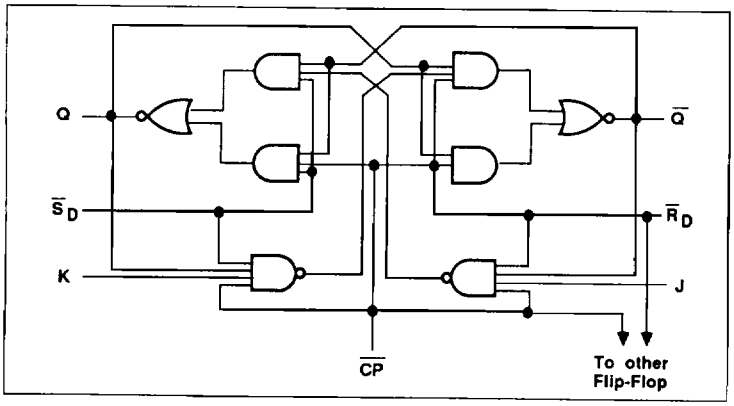


V_{CC} = pin 14
GND = pin 7

LOGIC SYMBOL(IEEE/IEC)



LOGIC DIAGRAM



FUNCTION TABLE

INPUTS					OUTPUTS		OPERATING MODE
$\overline{S}_D$	$\overline{R}_D$	$\overline{CP}$	J	K	Q	$\overline{Q}$	
L	H	X	X	X	H	L	Asynchronous Set
H	L	X	X	X	L	H	Asynchronous Reset
L	L	X	X	X	H*	H*	Undetermined *
H	H	↓	h	l	$\overline{q}$	q	Toggle
H	H	↓	l	l	L	H	Load "0"(Reset)
H	H	↓	h	l	H	L	Load "1" (Set)
H	H	↓	l	l	q	$\overline{q}$	Hold "no change"

H = High voltage level
h = High voltage level one setup time prior to High-to-Low clock transition
L = Low voltage level
l = Low voltage level one setup time prior to High-to-Low clock transition
q=Lower case letters indicate the state of the referenced output prior to the High-to-Low clock transition
X = Don't care
↓= High-to-Low clock transition
Asynchronous inputs: Low input to $\overline{S}_D$ sets Q to High level, Low input to $\overline{R}_D$ sets Q to Low level
Set and Reset are independent of clock
Simultaneous Low on both $\overline{S}_D$ and $\overline{R}_D$ makes both Q and $\overline{Q}$ High
* =Both outputs will be High while both $\overline{S}_D$ and $\overline{R}_D$ are Low, but the output states are unpredictable if $\overline{S}_D$ and $\overline{R}_D$ go High simultaneously.

ABSOLUTE MAXIMUM RATINGS

(Operation beyond the limits set forth in this table may impair the useful life of the device. Unless otherwise noted these limits are over the operating free-air temperature range.)

SYMBOL	PARAMETER	RATING	UNIT
V_{CC}	Supply voltage	-0.5 to +7.0	V
V_{IN}	Input voltage	-0.5 to +7.0	V
I_{IN}	Input current	-30 to +5	mA
V_{OUT}	Voltage applied to output in High output state	-0.5 to +V_{CC}	V
I_{OUT}	Current applied to output in Low output state	40	mA
T_A	Operating free-air temperature range	0 to +70	°C
T_{STG}	Storage temperature	-65 to +150	°C

RECOMMENDED OPERATING CONDITIONS

SYMBOL	PARAMETER	LIMITS			UNIT
		Min	Nom	Max	
V_{CC}	Supply voltage	4.5	5.0	5.5	V
V_{IH}	High-level input voltage	2.0			V
V_{IL}	Low-level input voltage			0.8	V
I_{IK}	Input clamp current			-18	mA
I_{OH}	High-level output current			-1	mA
I_{OL}	Low-level output current			20	mA
T_A	Operating free-air temperature range	0		70	°C

DC ELECTRICAL CHARACTERISTICS (Over recommended operating free-air temperature range unless otherwise noted.)

SYMBOL	PARAMETER		TEST CONDITIONS[1]		LIMITS			UNIT
					Min	Typ[2]	Max	
V_{OH}	High-level output voltage		V_{CC} = MIN, V_{IL} = MAX	±10%V_{CC}	2.5			V
			V_{IH} = MIN, I_{OH} = MAX	±5%V_{CC}	2.7	3.4		V
V_{OL}	Low-level output voltage		V_{CC} = MIN, V_{IL} = MAX	±10%V_{CC}		0.35	0.50	V
			V_{IH} = MIN, I_{OL} = MAX	±5%V_{CC}		0.35	0.50	V
V_{IK}	Input clamp voltage		V_{CC} = MIN, I_I = I_{IK}			-0.73	-1.2	V
I_I	Input current at maximum input voltage		V_{CC} =MAX, V_I = 7.0V				100	µA
I_{IH}	High-level input current		V_{CC} = MAX, V_I = 2.7V				20	µA
I_{IL}	Low-level input current	J_n, K_n	V_{CC} = MAX, V_i = 0.5V				-0.6	mA
		$\overline{CP}$					-4.8	mA
		$\overline{S}_{Dn}$					-3.0	mA
		$\overline{R}_D$					-6.0	mA
I_{OS}	Short-circuit output current[3]		V_{CC} = MAX		-60		-150	mA
I_{CC}	Supply current (total)[4]		V_{CC} = MAX			15	21	mA

NOTES:

1. For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable type.
2. All typical values are at V_{CC} = 5V, T_A = 25°C.
3. Not more than one output should be shorted at a time. For testing I_{OS}, the use of high-speed test apparatus and/or sample-and-hold techniques are preferable in order to minimize internal heating and more accurately reflect operational values. Otherwise, prolonged shorting of a High output may raise the chip temperature well above normal and thereby cause invalid readings in other parameter tests. In any sequence of parameter tests, I_{OS} tests should be performed last.
4. Measure I_{CC} with the clock input grounded and all outputs open, with the Q and $\overline{Q}$ outputs High in turn.

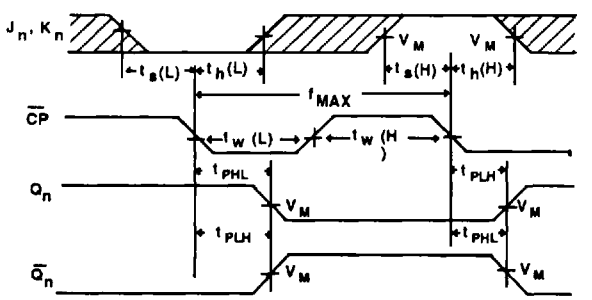
AC ELECTRICAL CHARACTERISTICS

SYMBOL	PARAMETER	TEST CONDITION	LIMITS					UNIT
			T_A = +25°C, V_{CC} = 5V, C_L = 50pF, R_L = 500Ω			T_A = 0°C to +70°C, V_{CC} = 5V ±10%, C_L = 50pF, R_L = 500Ω		
			Min	Typ	Max	Min	Max	
f_{MAX}	Maximum clock frequency	Waveform 1	85	100		80		MHz
t_{PLH} t_{PHL}	Propagation delay $\overline{CP}$ to Q_n or $\overline{Q}_n$	Waveform 1	2.0 2.0	5.0 5.5	6.5 7.5	2.0 2.0	7.5 8.5	ns
t_{PLH} t_{PHL}	Propagation delay $\overline{S}_{Dn}$, $\overline{R}_D$ to Q_n or $\overline{Q}_n$	Waveform 2,3	2.0 2.0	4.5 4.5	6.5 6.5	2.0 2.0	7.5 7.5	ns

AC SETUP REQUIREMENTS

SYMBOL	PARAMETER	TEST CONDITION	LIMITS					UNIT
			T_A = +25°C, V_{CC} = 5V, C_L = 50pF, R_L = 500Ω			T_A = 0°C to +70°C, V_{CC} = 5V ±10%, C_L = 50pF, R_L = 500Ω		
			Min	Typ	Max	Min	Max	
$t_s(H)$ $t_s(L)$	Setup time, High or Low J_n, $\overline{K}_n$ to $\overline{CP}$	Waveform 1	4.0 3.5			5.0 4.0		ns
$t_h(H)$ $t_h(L)$	Hold time, High or Low J_n, $\overline{K}_n$ to $\overline{CP}$	Waveform 1	0.0 0.0			0.0 0.0		ns
$t_w(H)$ $t_w(L)$	$\overline{CP}$ Pulse width High or Low	Waveform 1	4.5 4.5			5.0 5.0		ns
$t_w(L)$	$\overline{S}_{Dn}$, $\overline{R}_D$ Pulse width Low	Waveform 2,3	4.5			5.0		ns
t_{REC}	Recovery time $\overline{S}_{Dn}$, $\overline{R}_D$ to $\overline{CP}$	Waveform 2,3	4.5			5.0		ns

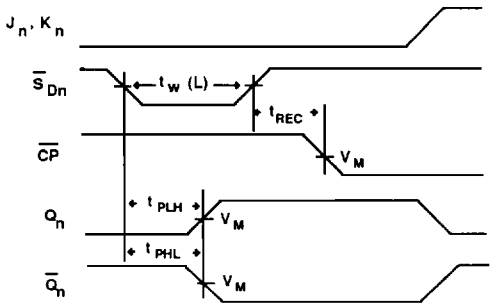
AC WAVEFORMS



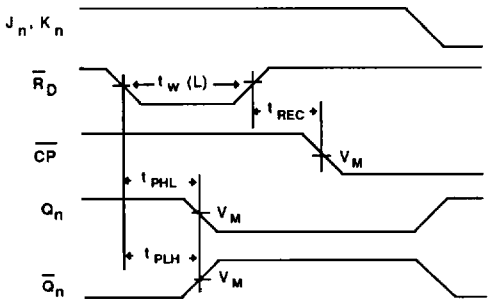
Waveform 1. Propagation Delay for Data to Output, Data Setup Time and Hold Times, and Clock Width

NOTE: For all waveforms, V_M = 1.5V.
The shaded areas indicate when the input is permitted to change for predictable output performance.

AC WAVEFORMS



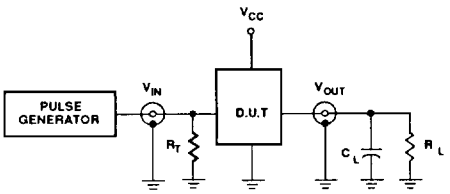
Waveform 2.
Propagation Delay for Set to Output, Set
Pulse Width, and Recovery Time for Set to clock



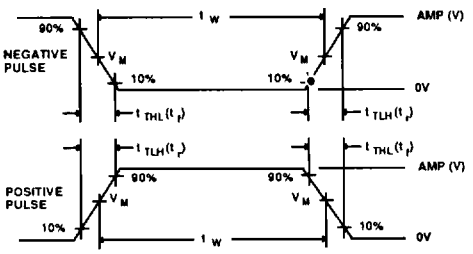
Waveform 3.
Propagation Delay forReset to Output, Reset
Pulse Width, and Recovery Time for Reset to Clock

NOTE: For all waveforms, V_M = 1.5V.

TEST CIRCUIT AND WAVEFORMS



Test Circuit For Totem-Pole Outputs



V_M = 1.5V

Input Pulse Definition

DEFINITIONS

R_L = Load resistor; see AC CHARACTERISTICS for value.

C_L = Load capacitance includes jig and probe capacitance; see AC CHARACTERISTICS for value.

R_T = Termination resistance should be equal to Z_{OUT} of pulse generators.

FAMILY	INPUT PULSE REQUIREMENTS				
	Amplitude	Rep. Rate	t_W	t_{TLH}	t_{THL}
74F	3.0V	1MHz	500ns	2.5ns	2.5ns